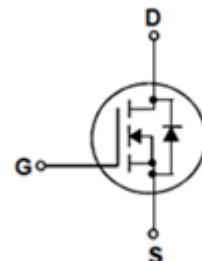
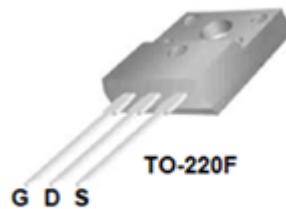


## 650V N-Channel MOSFET

### General Description

This Power MOSFET is produced using advanced planar stripe DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency switched mode power supplies, active power factor correction based on half bridge topology.



### Features

10A, 650V,  $R_{DS(on)}$ typ. =  $0.7\Omega$ @ $V_{GS} = 10\text{ V}$

Smart design in high voltage technology

Ultra low gate charge

Fast switching

Low reverse recovery charge.

Improved dv/dt capability

### Absolute Maximum Ratings $T_c = 25\text{ }^\circ\text{C}$ unless otherwise noted

| Symbol          | Parameter  |  | JFFC10N65D  | Units                             |
|-----------------|--|--|-------------|-----------------------------------|
| $V_{DSS}$       | Drain – Source Voltage   |  | 650         | V                                 |
| $I_D$           | Drain Current  | Continuous ( $T_c = 25\text{ }^\circ\text{C}$ )  | 10*         | A                                 |
|                 |  | Continuous ( $T_c = 100\text{ }^\circ\text{C}$ ) | 6*          | A                                 |
| $I_{DM}$        | Drain Current - Pulsed<br>( Note 1 )   |  | 40          | A                                 |
| $V_{GSS}$       | Gate – Source Voltage  |  | $\pm 30$    | V                                 |
| EAS             | Single Pulsed Avalanche Energy<br>( Note 2 )   |  | 161         | mJ                                |
| $I_{AR}$        | Avalanche Current<br>( Note 1 )  |  | 10          | A                                 |
| E <sub>AR</sub> | Repetitive Avalanche Energy<br>( Note 1 )  |  | 20          | mJ                                |
| $dv/dt$         | Peak Diode Recovery $dv/dt$<br>( Note 3 )  |  | 4.5         | V/ns                              |
| $P_D$           | Power Dissipation ( $T_c = 25\text{ }^\circ\text{C}$ )<br>-Derate above $25\text{ }^\circ\text{C}$ |  | 39          | W                                 |
|                 |  |  | 0.32        | $\text{W}/\text{ }^\circ\text{C}$ |
| $T_J, T_{STG}$  | Operating and Storage Temperature Range  |  | -55 to +150 | $^\circ\text{C}$                  |
| $T_L$           | Maximum lead temperature for soldering purposes<br>1/8" from case for 5 seconds                    |  | 300         | $^\circ\text{C}$                  |

\*Drain current limited by maximum junction temperature.

## Thermal characteristics

| Symbol         | Parameter                               | JFFC10N65D |  |  | Units |
|----------------|---|------------|--|--|-------|
| $R_{\thetaJC}$ | Thermal Resistance, Junction-to-Case    | 3.2        |  |  | °C/W  |
| $R_{\thetaJS}$ | Thermal Resistance, Case-to-Sink Typ.   | --         |  |  | °C/W  |
| $R_{\thetaJA}$ | Thermal Resistance, Junction-to-Ambient | 62.5       |  |  | °C/W  |

## Electrical Characteristics $T_c = 25^\circ C$ unless otherwise noted

| Symbol  | Parameter   | Test Conditions  | Min | Typ  | Max  | Units |
|---|---|--|-----|------|------|-------|
| <b>Off Characteristics</b>                                      |   |  |     |      |      |       |
| $BV_{DSS}$  | Drain – Source Breakdown Voltage                      | $V_{GS} = 0 V, I_D = 250 \mu A$  | 650 | --   | --   | V     |
| $\Delta BV_{DSS}/\Delta T_J$                                    | Breakdown Voltage Temperature Coefficient             | $I_D = 250 \mu A$ , Referenced to $25^\circ C$                           | --  | 0.6  | --   | V/°C  |
| $I_{DSS}$   | Zero Gate Voltage Drain Current                       | $V_{DS} = 650 V, V_{GS} = 0 V$   | --  | --   | 1    | uA    |
|   |   | $V_{DS} = 520 V, T_c = 125^\circ C$                                      | --  | --   | 10   | uA    |
| $I_{GSSF}$  | Gate-Body Leakage Current, Forward                    | $V_{GS} = 30 V, V_{DS} = 0 V$  | --  | --   | 100  | nA    |
| $I_{GSSR}$  | Gate-Body Leakage Current, Reverse                    | $V_{GS} = -30 V, V_{DS} = 0 V$   | --  | --   | -100 | nA    |
| <b>On Characteristics</b>                                       |   |  |     |      |      |       |
| $V_{GS(th)}$  | Gate Threshold Voltage                                | $V_{DS} = V_{GS}, I_D = 250 \mu A$                                       | 2.0 | --   | 4.0  | V     |
| $R_{DS(on)}$  | Static Drain-Source on-Resistance                     | $V_{GS} = 10 V, I_D = 5 A$   | --  | 0.7  | 0.85 | Ω     |
| $g_{FS}$  | Forward Transconductance                              | $V_{DS} = 40 V, I_D = 5 A$ ( Note 4 )                                    | --  | 9    | --   | S     |
| <b>Dynamic Characteristics</b>                                  |   |  |     |      |      |       |
| $C_{iss}$   | Input Capacitance                                     | $V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 \text{ MHz}$                       | --  | 1850 | --   | pF    |
| $C_{oss}$   | Output Capacitance                                    |  | --  | 165  | --   | pF    |
| $C_{rss}$   | Reverse Transfer Capacitance                          |  | --  | 8.5  | --   | pF    |
| <b>Switching Characteristics</b>                                |   |  |     |      |      |       |
| $t_{d(on)}$   | Turn-On Delay Time                                    | $V_{DS} = 325 V, I_D = 10.0 A, R_G = 25\Omega, V_{GS} = 10 V$ (Note 4,5) | --  | 32   | --   | ns    |
| $t_r$   | Turn-On Rise Time                                     |  | --  | 28   | --   | ns    |
| $t_{d(off)}$  | Turn-Off Delay Time                                   |  | --  | 161  | --   | ns    |
| $t_f$   | Turn-Off Fall Time                                    |  | --  | 48.5 | --   | ns    |
| $Q_g$   | Total Gate Charge                                     | $V_{DS} = 520 V, I_D = 10.0 A, V_{GS} = 10 V$ (Note 4,5)                 | --  | 38.5 | --   | nC    |
| $Q_{gs}$  | Gate-Source Charge                                    |  | --  | 8.5  | --   | nC    |
| $Q_{gd}$  | Gate-Drain Charge                                     |  | --  | 14.5 | --   | nC    |
| <b>Drain – Source Diode Characteristics and Maximum Ratings</b> |   |  |     |      |      |       |
| $I_S$   | Maximum Continuous Drain-Source Diode Forward Current | --   | --  | 10   | A    |       |
| $I_{SM}$  | Maximum Pulsed Drain-Source Diode Forward Current     | --   | --  | 40   | A    |       |
| $V_{SD}$  | Drain-Source Diode Forward Voltage                    | $V_{GS} = 0 V, I_S = 10.0 A$   | --  | --   | 1.4  | V     |
| $t_{rr}$  | Reverse Recovery Time                                 | $V_{GS} = 0 V, I_S = 10.0 A, dI/dt = 100 A/us$ ( Note 4 )                | --  | 400  | --   | ns    |
| $Q_{rr}$  | Reverse Recovery Charge                               |  | --  | 4.4  | --   | uC    |

### Notes:

- Repetitive Rating : Pulsed width limited by maximum junction temperature
- $L = 3.0mH, I_{AS} = 10A, V_{DD} = 50V, R_G = 25\Omega$ , Starting  $T_J = 25^\circ C$
- $I_{SD} \leq 13.0A, di/dt \leq 200A/us, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ C$
- Pulsed Test : Pulsed width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$
- Essentially independent of operating temperature

## Typical Characteristics

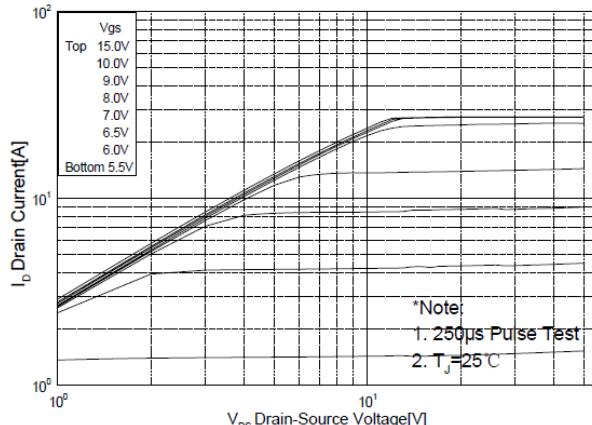


Figure 1. On-Region Characteristics

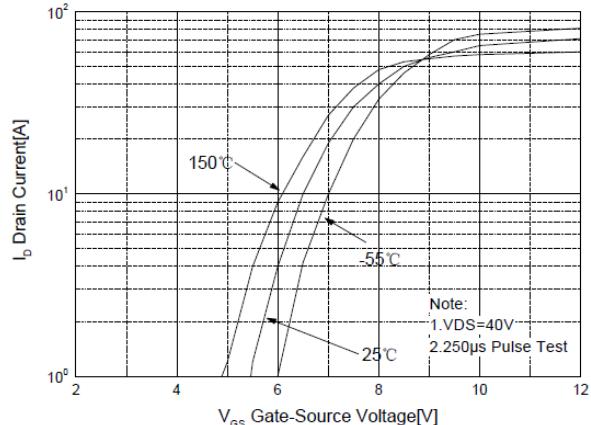


Figure 2. Transfer Characteristics

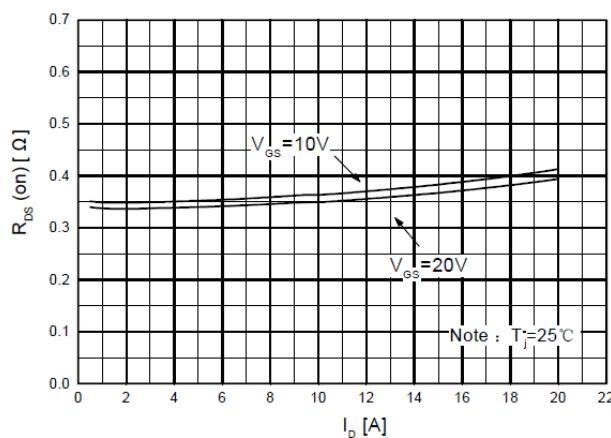


Figure 3. On-Resistance Variation vs  
Drain Current and Gate Voltage

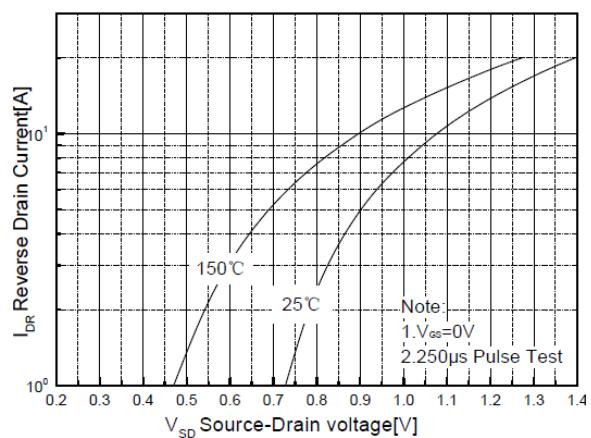


Figure 4. Body Diode Forward Voltage  
Variation with Source Current  
and Temperature

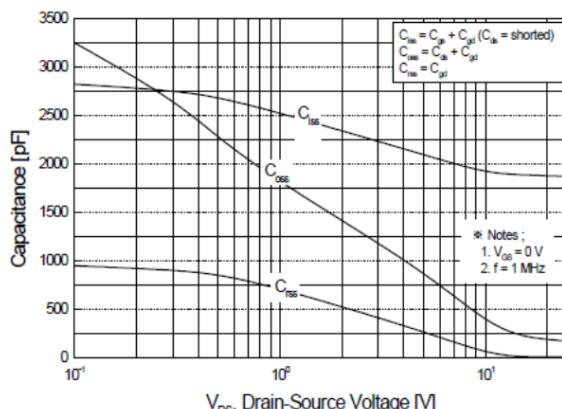


Figure 5. Capacitance Characteristics

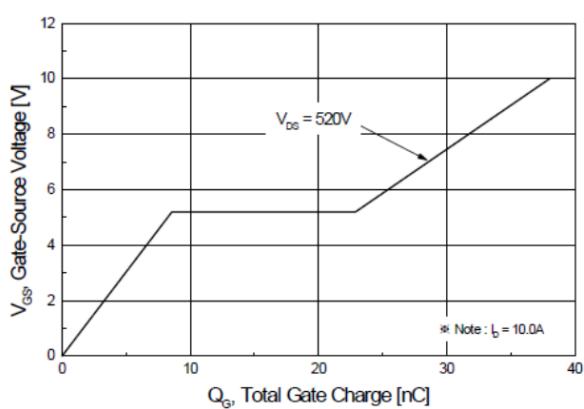


Figure 6. Gate Charge Characteristics



## Typical Characteristics

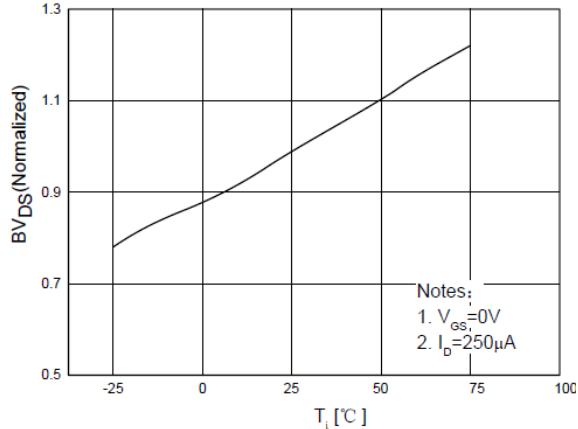


Figure 7. Breakdown Voltage Variation  
vs Temperature

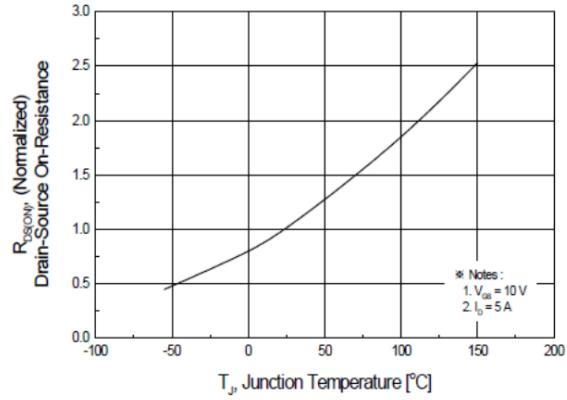


Figure 8. On-Resistance Variation  
vs Temperature

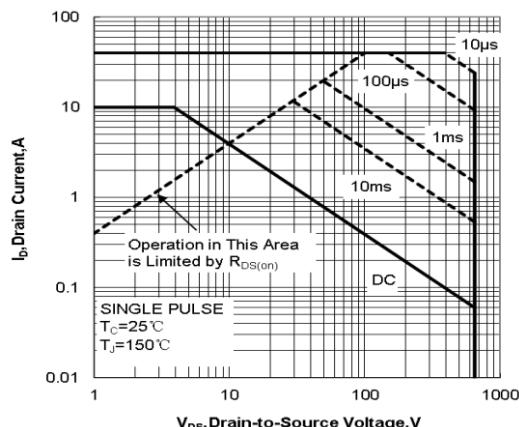


Figure 9-2. Maximum Safe Operating Area

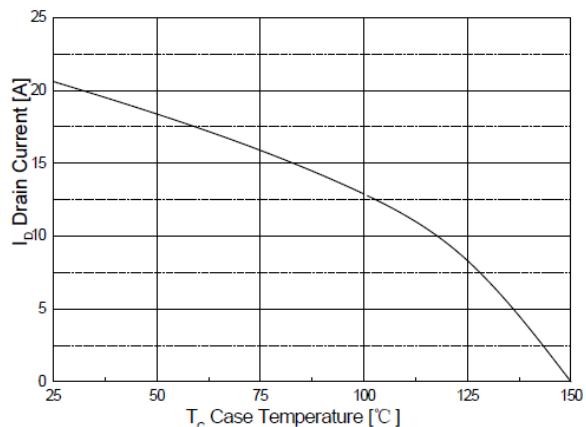


Figure 10. Maximum Drain Current  
vs Case Temperature

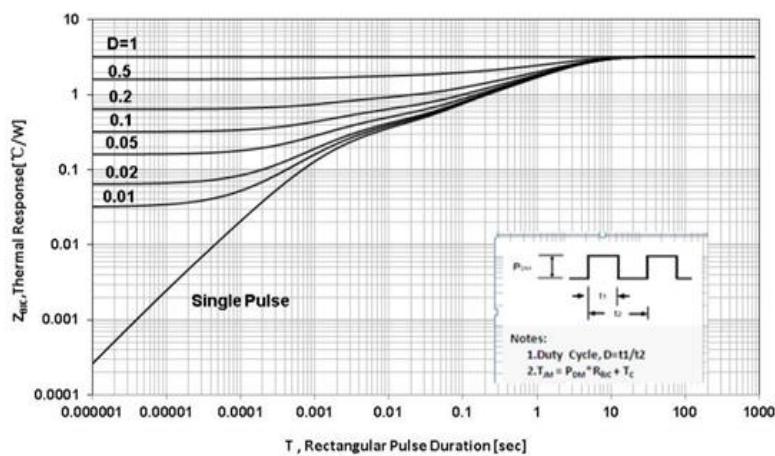
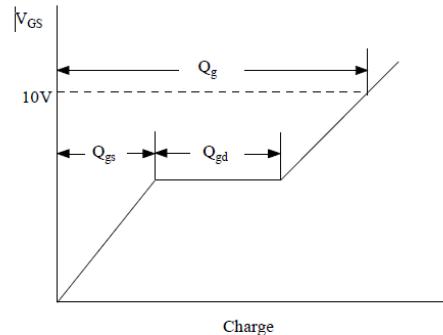
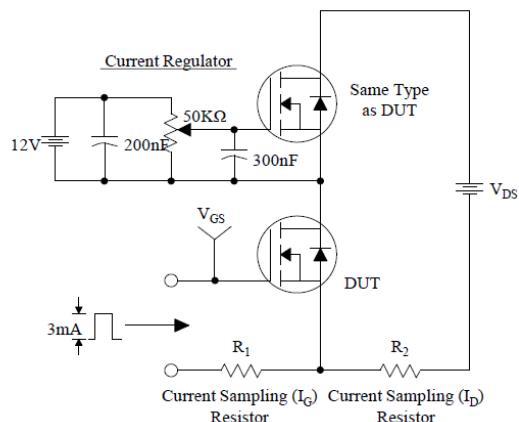


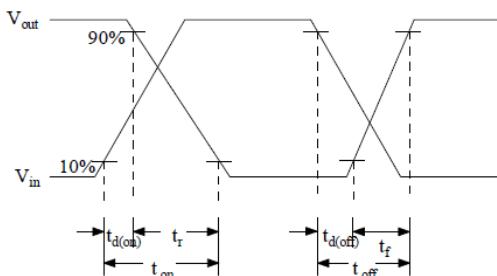
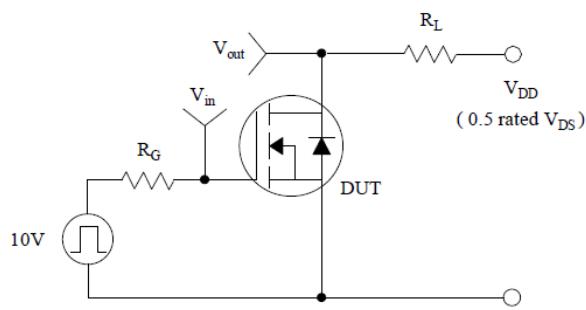
Figure 11. Transient Thermal Response Curve for JFFC10N65D



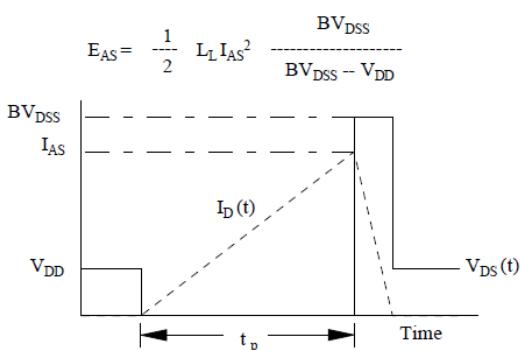
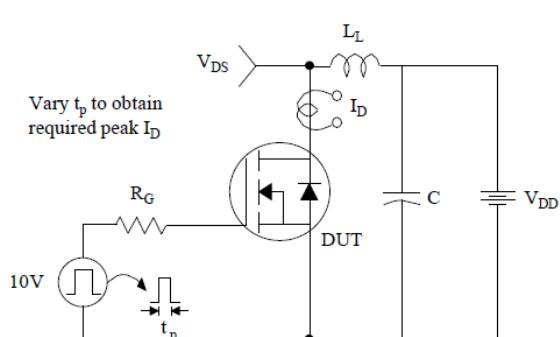
## Test Circuit & Waveform



Gate Charge Test Circuit & Waveform



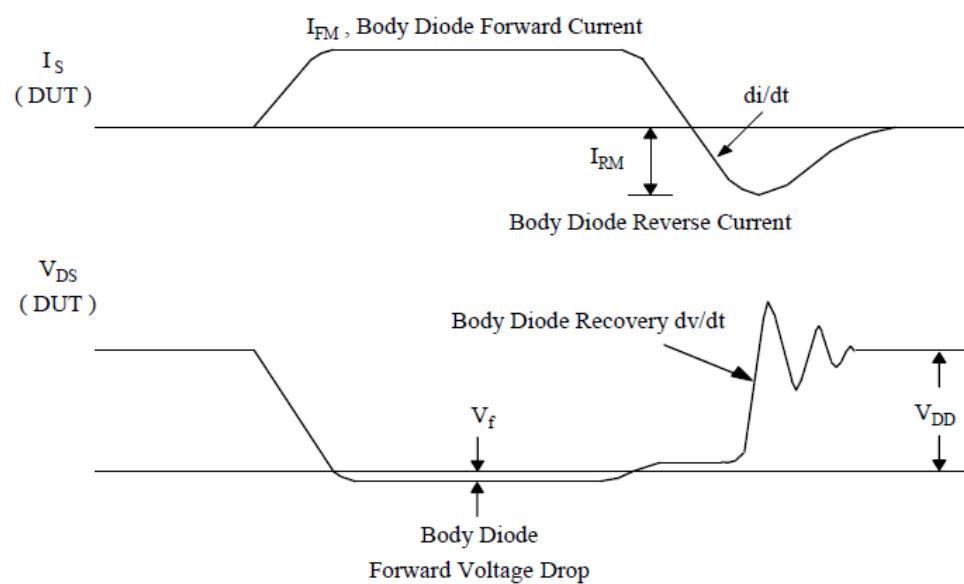
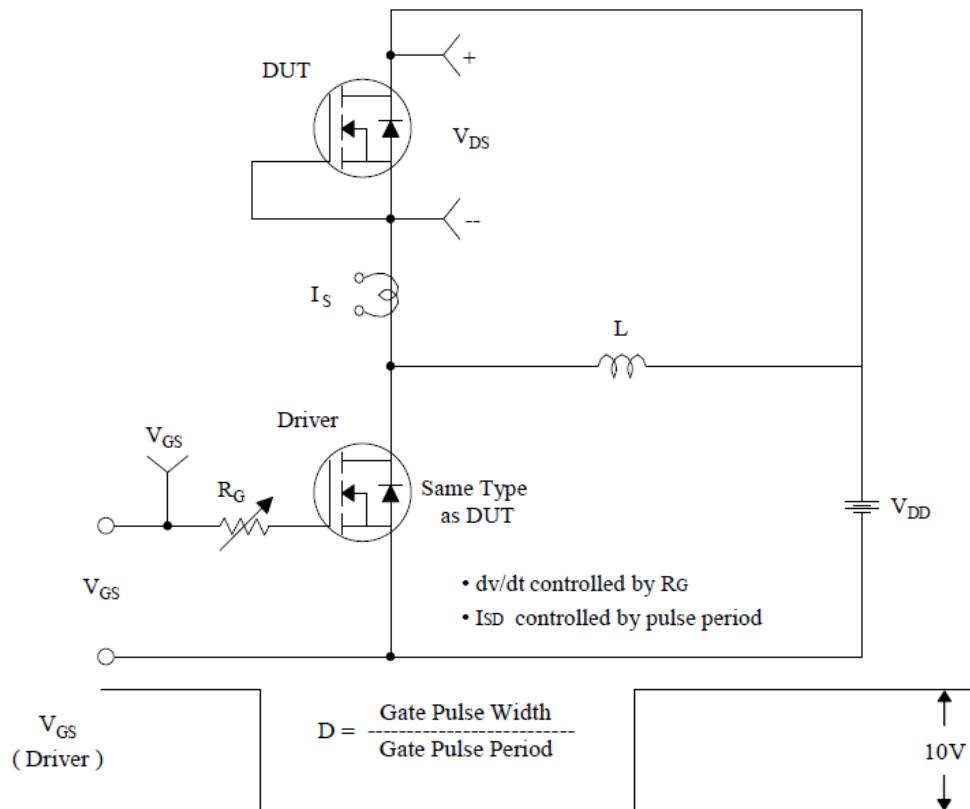
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



## Test Circuit &amp; Waveform

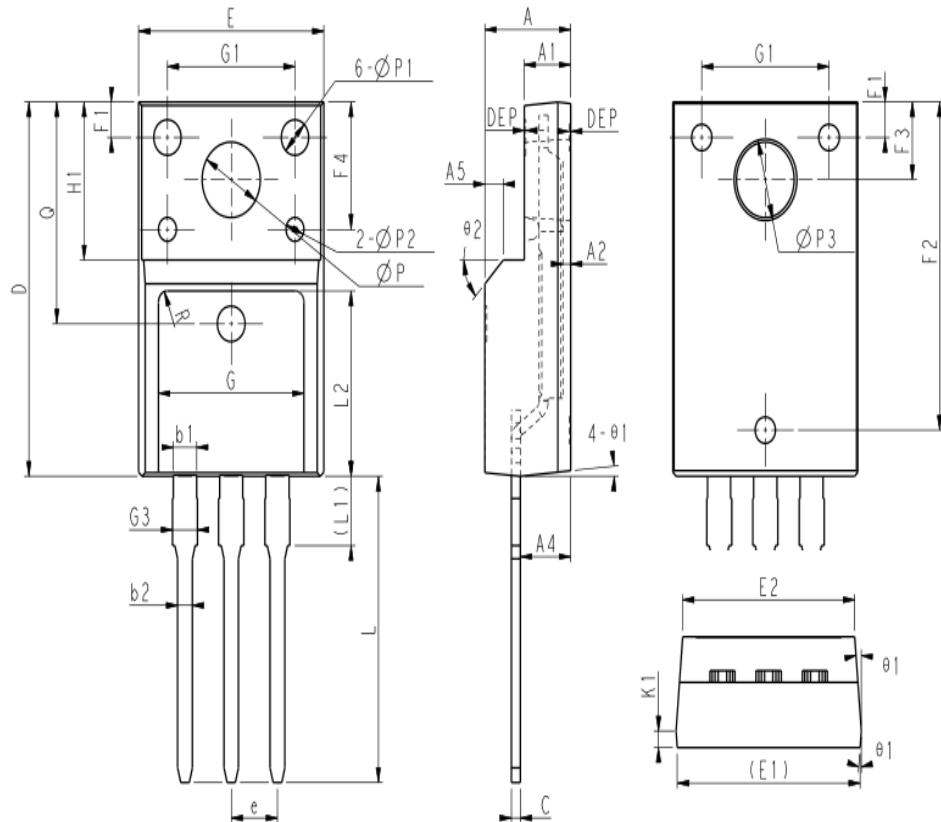
Peak Diode Recovery  $dv/dt$  Test Circuit & Waveforms



佳恩半导体  
JIAENSEMI

JFFC10N65D

## Packaging



COMMON DIMENSIONS

| SYMBOL | MM      |       |       |
|--------|---------|-------|-------|
|        | MIN     | NOM   | MAX   |
| E      | 10.00   | 10.16 | 10.32 |
| E1     | 9.94    | 10.04 | 10.14 |
| E2     | 9.36    | 9.46  | 9.56  |
| A      | 4.50    | 4.70  | 4.90  |
| A1     | 2.34    | 2.54  | 2.74  |
| A2     | 0.43    | -     | 0.48  |
| A3     | 2.66    | 2.76  | 2.86  |
| A5     | 1.00REF |       |       |
| c      | 0.45    | 0.50  | 0.60  |
| D      | 15.67   | 15.87 | 16.07 |
| Q      | 9.40REF |       |       |
| H1     | 6.70REF |       |       |
| e      | 2.54BSC |       |       |
| ΦP     | 3.18REF |       |       |
| L      | 12.78   | 12.98 | 13.18 |
| L1     | 2.83    | 2.93  | 3.03  |
| L2     | 7.70    | 7.80  | 7.90  |
| ΦP1    | 1.40    | 1.50  | 1.60  |
| ΦP2    | 0.95    | 1.00  | 1.05  |
| ΦP3    | 3.45REF |       |       |
| θ1     | 3°      | 5°    | 7°    |
| θ2     | -       | 45°   | -     |
| DEP    | 0.05    | 0.10  | 0.15  |
| F1     | 1.00    | 1.50  | 2.00  |
| F2     | 13.80   | 13.90 | 14.00 |
| F3     | 3.20    | 3.30  | 3.40  |
| F4     | 5.30    | 5.40  | 5.50  |
| G      | 7.80    | 8.00  | 8.20  |
| G1     | 6.90    | 7.00  | 7.10  |
| G3     | 1.25    | 1.35  | 1.45  |
| b1     | 1.23    | 1.28  | 1.38  |
| b2     | 0.75    | 0.80  | 0.90  |
| K1     | 0.65    | 0.70  | 0.75  |
| R      | 0.50REF |       |       |

## **Disclaimers**

JIAEN Semiconductor Co., Ltd reserves the right to make changes without notice in order to improve reliability, function or design and to discontinue any product or service without notice. Customers should obtain the latest relevant information before orders and should verify that such information is current and complete. All products are sold subject to JIAEN's terms and conditions supplied at the time of order acknowledgement.

JIAEN Semiconductor Co., Ltd warrants performance of its hardware products to the specifications at the time of sale, Testing, reliability and quality control are used to the extent JIAEN deems necessary to support this warranty. Except where agreed upon by contractual agreement, testing of all parameters of each product is not necessarily performed.

JIAEN Semiconductor Co., Ltd does not assume any liability arising from the use of any product or circuit designs described herein. Customers are responsible for their products and applications using JIAEN's components. To minimize risk, customers must provide adequate design and operating safeguards.

JIAEN Semiconductor Co., Ltd does not warrant or convey any license either expressed or implied under its parent rights, nor the rights of others. Reproduction of information in JIAEN's datasheets or data books is permissible only if reproduction is without modification or alteration. Reproduction of this information with any alteration is an unfair and deceptive business practice. JIAEN Semiconductor Co., Ltd is not responsible or liable for such altered documentation.

Resale of JIAEN's products with statements different from or beyond the parameters stated by JIAEN Semiconductor Co., Ltd for that product or service voids all express or implied warranties for the associated JIAEN's product or service and is unfair and deceptive business practice. JIAEN Semiconductor Co., Ltd is not responsible or liable for any such statements.